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Sheet 1 of 1

Form PTO-1449 (REV. 1/06)  US Dept. of Commerce PATENT & TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)	ATTY DOCKET NO. 128503	APPLICATION NO. New U.S. Patent Application 10584771
	APPLICANT Isao YOKOKAWA	
	FILING DATE June 28, 2006	GROUP 2812

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
/CL/	1	JP A 2001-217430	8/10/2001	Japan	X	X
	2	JP A 2002-164520	6/7/2002	Japan	X	X
	3	JP A 2002-305293	10/18/2002	Japan	X	X
	4	JP A 2003-229360	8/15/2003	Japan	X	X
	5	JP A 2003-229361	8/15/2003	Japan	X	X
	6	JP A 2000-286413	10/13/2000	Japan	X	X
/CL/	7	JP A 11-304729	11/5/1999	Japan	X	X

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)
/CL/	8	M. Erdtmann et al, "Structural Characterization of Strained Silicon Substrates by X-Ray Diffraction and Reflectivity", Extended Abstracts of the 2003 International Conference on Solid State Devices and Material, Tokyo, pp. 290-291, 2003.
/CL/	9	W.L. Bond, "Precision Lattice Constant Determination", Acta Crystallographica, pp. 814-818, October 10, 1960.

EXAMINER /Cheung Lee/	DATE CONSIDERED 11/07/2008
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Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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